



N-26-04

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PATENT
Attorney Docket No.: 34554/US/2
Express Mail Label No.: EV 423776646 US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Applicant	: Kenneth R. Wilsher	Patent No.	: 6,819,117 B2
Appln. No.	: 10/066,123	Issue Date	: November 16, 2004
Filed	: January 30, 2002	Confirmation No.:	5687
Title	: PICA SYSTEM TIMING MEASUREMENT AND CALIBRATION	Group Art Unit	: 2133
		Examiner	: Kerveros, James C.

CERTIFICATE OF MAILING BY EXPRESS MAIL

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Certificate
NOV 30 2004
of Correction

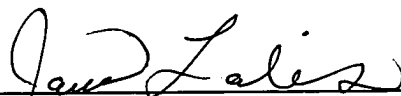
Sir:

The undersigned hereby certifies that the following documents:

1. Request for Certificate of Correction (2 pages);
2. Certificate of Correction (2 pages);
3. Copy of Information Disclosure Statement filed 05/25/2002 (5 pages);
4. Copy of Initialed Form PTO-1449 (2 pages);
5. Certificate of Mailing by Express Mail (1 page); and
6. Return Card

relating to the above application, were deposited as "Express Mail" under 37 CFR § 1.10,
Mailing Label No. EV 423776646 US, with the United States Postal Service addressed to
Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on

November 23, 2004.



Mailer's Signature

Print Name: Jane M. Lalis

Dorsey & Whitney LLP

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Fax: 303-629-3450

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		Examiner	: Kerveros, James C.

REQUEST FOR CERTIFICATE OF CORRECTION
(37 C.F.R. §§ 1.322)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Applicant hereby requests a Certificate of Correction under 37 C.F.R. § 1.322 be issued for the above patent, in accordance with the attached request.

References cited in an Information Disclosure Statement by the Applicant on May 25, 2002, and initialed by the Examiner on July 7, 2003, were omitted from the cover page of the issued patent. A copy of the originally filed Information Disclosure Statement and the Examiner's initialed copy are enclosed.

All errors sought to be corrected were made by the Patent Office. Therefore, no fee is believed due with this filing. However, should any fees or petitions be required, please consider this a request therefor and authorization to charge Deposit Account No. 04-1415 as necessary.

DEC 03 2004



PATENT
Attorney Docket No.: 34554/US/2
Express Mail Label No.: EV 423776646 US

Should the Examiner have any questions, please contact the undersigned
attorney.

Dated: 23 November 2004.

Respectfully submitted,

Gregory P. Durbin, Registration No. 42,503
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UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 6,819,117 B2
ISSUE DATE : November 16, 2004
INVENTOR(S) : Kenneth R. Wilsher

It is certified that an error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

On the cover page, under "U.S. Patent Documents", insert --5,940,545 08/1999 Kash et al.--

On the cover page, under "U.S. Patent Documents", insert --6,028,952 02/2000 Kash et al.--

On the cover page, under "U.S. Patent Documents", insert --6,172,512 01/2001 Evans et al.--

On the cover page, under "U.S. Patent Documents", insert --6,304,668 10/2001 Evans et al.--

On the cover page, under "Other Publications", insert --J. Bude, *Hot-carrier luminescence in Si*, PHYS. REV. B, 45(11), 15 March 1992, pages 5848-5856--

On the cover page, under "Other Publications", insert --S. Villa *et al.*, *Photon emission from hot electrons in silicon*, PHYS. REV. B, 52(15), 15 October 1995-I, pages 10993-10999--

On the cover page, under "Other Publications", insert --J. Kash *et al.*, *Full Chip Optical Imaging of Logic State Evolution in CMOS Circuits*, IEDM 96 Late News Paper (1996) 1, pages 934-936--

On the cover page, under "Other Publications", insert --D. Knebel *et al.*, *Diagnosis and Characterization of Timing-Related Defects by Time-Dependent Light Emission*, ITC PROCEEDINGS 1998--

On the cover page, under "Other Publications", insert --M. Bruce *et al.*, *Waveform Acquisition from the Backside of Silicon Using Electro-Optic Probing*, PROCEEDINGS FROM THE 25th INTERNATIONAL SYMPOSIUM FOR TESTING AND FAILURE ANALYSIS, 14-18 November 1999, pages 19-25--

Mailing address of Sender:

Patent No. 6,819,117 B2

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USPTO Customer No.: 20686

DEC 03 2004

**UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION (continued)**

PATENT NO. : 6,819,117 B2
ISSUE DATE : November 16, 2004
INVENTOR(S) : Kenneth R. Wilsher

It is certified that an error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

On the cover page, under "Other Publications", insert --T. Eiles *et al.*, *Optical Probing of VLSI IC's from the Silicon Backside*, PROCEEDINGS FROM THE 25TH INTERNATIONAL SYMPOSIUM FOR TESTING AND FAILURE ANALYSIS, 14-18 November 1999, pages 27-33--

On the cover page, under "Other Publications", insert --M. McManus, *Picosecond Imaging Circuit Analysis of the IBM G6 Microprocessor Cache*, PROCEEDINGS FROM THE 25TH INTERNATIONAL SYMPOSIUM FOR TESTING AND FAILURE ANALYSIS, 14-18 November 1999, pages 35-38--

On the cover page, under "Other Publications", insert --N. Goldblatt *et al.*, *Unique and Practical IC Timing Analysis Tool Utilizing Intrinsic Photon Emission*, MICROELECTRONICS RELIABILITY 41 (2001) 1507-1512--

On the cover page, under "Other Publications", insert --G. Dajee *et al.*, *Practical, Non-Invasive Optical Probing for Flip-Chip Devices*, ITC Paper 15.3 (Baltimore, October 28 – November 2, 2001) 433-442--

On the cover page, under "Other Publications", insert --IDS® *PICA, Advanced Optical Imaging for Analysis of 0.13-micron and SOI Devices*, Schlumberger Semiconductor Solutions brochure printed 3/01, four pages--

On the cover page, insert --FOREIGN PATENT DOCUMENTS 0 937 989 A2 08/1999 EPO--

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Patent No. 6,819,117 B2

DEC 03 2004



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Attorney Dkt 65.0372

Kenneth R. WILSHER

Group Art Unit: 2825

Serial No.: 10/066,123

Examiner:

Filed: January 30, 2002

For: PICA System Timing Measurement & Calibration

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on May 25, 2002.

May 25, 2002


Bruce D. Riter, Reg. No. 27,379

DISCLOSURE STATEMENT UNDER 37 CFR §§1.56, 1.97 & 1.98

HON. COMMISSIONER OF PATENTS AND TRADEMARKS
Washington, D.C. 20231

Sir:

Transmitted herewith are the following:

1. Copies of the following document(s):
 - a. U.S. Patent No. 5,940,545 of Kash *et al.*, dated Aug. 17, 1999
 - b. U.S. Patent No. 6,028,952 of Kash *et al.*, dated Feb. 22, 2000
 - c. U.S. Patent No. 6,172,512 B1 of Evans *et al.*, dated Jan, 9, 2001
 - d. U.S. Patent No. 6,304,668 B1 of Evans *et al.*, dated Oct. 16, 2001
 - e. European Patent Application EP 0 937 989 A2 published 25.08.1999
 - f. J. BUDE, *Hot-carrier luminescence in Si*, PHYS. REV. B, 45(11), 15 March 1992, pages 5848-5856

- g. S. VILLA *et al.*, *Photon emission from hot electrons in silicon*, PHYS. REV. B, 52(15), 15 October 1995-I, pages 10993-10999
 - h. J. KASH *et al.*, *Full Chip Optical Imaging of Logic State Evolution in CMOS Circuits*, IEDM 96 Late News Paper (1996) 1, pages 934-936
 - i. D. KNEBEL *et al.*, *Diagnosis and Characterization of Timing-Related Defects by Time-Dependent Light Emission*, ITC PROCEEDINGS 1998
 - j. M. BRUCE *et al.*, *Waveform Acquisition from the Backside of Silicon Using Electro-Optic Probing*, PROCEEDINGS FROM THE 25TH INTERNATIONAL SYMPOSIUM FOR TESTING AND FAILURE ANALYSIS, 14-18 November 1999, pages 19-25
 - k. T. EILES *et al.*, *Optical Probing of VLSI IC's from the Silicon Backside, Proceedings from the 25th International Symposium for Testing and Failure Analysis*, 14-18 November 1999, pages 27-33
 - l. M. MCMANUS, *Picosecond Imaging Circuit Analysis of the IBM G6 Microprocessor Cache*, PROCEEDINGS FROM THE 25TH INTERNATIONAL SYMPOSIUM FOR TESTING AND FAILURE ANALYSIS, 14-18 November 1999, pages 35-38
 - m. N. GOLDBLATT *et al.*, *Unique and Practical IC Timing Analysis Tool Utilizing Intrinsic Photon Emission*, MICROELECTRONICS RELIABILITY 41 (2001) 1507-1512
 - n. G. DAJEE *et al.*, *Practical, Non-Invasive Optical Probing for Flip-Chip Devices*, ITC Paper 15.3 (Baltimore, October 28 - November 2, 2001) 433-442
 - o. IDS® PICA, *Advanced Optical Imaging for Analysis of 0.13-micron and SOI Devices*, Schlumberger Semiconductor Solutions brochure printed 3/01, four pages
2. A listing of the above-identified document(s) on a separate sheet entitled Information Disclosure Citation, as a substitute for form PTO-1449.

This Disclosure Statement is believed to be submitted before the mailing date of a first Office action on the merits. Pursuant to 37 CFR §1.97(b), Applicants respectfully request that the enclosed document be considered.

Applicants further request that the enclosed documents listed above be made of record for printing on any patent which may issue from this application, that the enclosed substitute for Form PTO-1449 be initialed to indicate that the documents have been considered, and that a copy of the initialed substitute for Form PTO-1449 be returned to the undersigned.

If this Disclosure Statement is not submitted prior to the mailing date of a first Office action on the merits, Applicants respectfully request that the enclosed document be considered under 37 CFR §1.97(c).

May 25, 2002

The Commissioner is hereby authorized to charge fees under 37 CFR §1.17 that may be required, or credit any overpayment, to deposit Account No. 19-0603 maintained in the name of Schlumberger Technologies, Inc. A duplicate of this paper is enclosed.

May 25, 2002

Respectfully Submitted,



Bruce D. Riter, Reg. No. 27,379
101 First Street, PMB 208
Los Altos, California 94022-2750

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Institute for Form PTO-1449
U.S. Department of Commerce
Patent and Trademark Office

Atty. Docket No. 65.0372
Serial No. 10/066,123
Applicant: Kenneth R. WILSHER
Filing Date: January 30, 2002
Group Art Unit: 2825

INFORMATION DISCLOSURE CITATION

Submitted May 25, 2002

U.S. Patent Documents

<u>Examiner Initial</u>	<u>Document Number</u>	<u>Date</u>	<u>Name</u>
_____	5,940,545	Aug. 17, 1999	Kash <i>et al.</i>
_____	6,028,952	Feb. 22, 2000	Kash <i>et al.</i>
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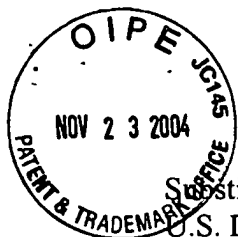
Foreign Patent Documents

<u>Examiner Initial</u>	<u>Document Number</u>	<u>Date</u>	<u>Country</u>
_____	0 937 989 A2	25.08.1999	European Patent Office

Other Documents

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Substitute for Form PTO-1449
U.S. Department of Commerce
Patent and Trademark Office

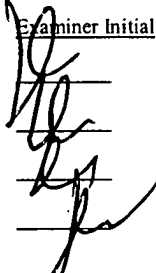
Atty. Docket No. 65.0372
Serial No. 10/066,123
Applicant: Kenneth R. WILSHER
Filing Date: January 30, 2002
Group Art Unit: 2825



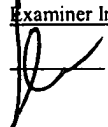
INFORMATION DISCLOSURE CITATION

Submitted May 25, 2002

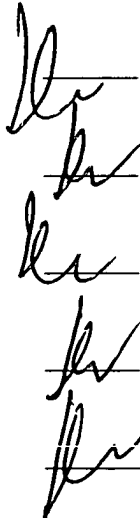
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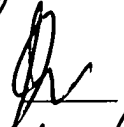

Other Documents

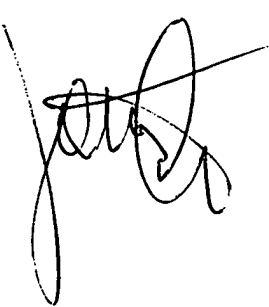
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